TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSIII)

2SK2884

Chopper Regulator, DC-DC Converter Applications

 $\begin{array}{ll} \bullet & Low \ drain-source \ ON \ resistance & : \ RDS \ (ON) = 1.9 \ \Omega \ (typ.) \\ \bullet & High \ forward \ transfer \ admittance & : \ |Y_{fs}| = 3.8 \ S \ (typ.) \\ \bullet & Low \ leakage \ current & : \ IDSS = 100 \ \mu A \ (max) \ (VDS = 640 \ V) \\ \bullet & Enhancement \ mode & : \ V_{th} = 2.0 \sim 4.0 \ V \ (VDS = 10 \ V, \ ID = 1 \ mA) \\ \end{array}$

Absolute Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	800	V	
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	800	V	
Gate-source voltage		V_{GSS}	±30	٧	
Drain current	DC (Note 1)	I _D	5	Α	
	Pulse (Note 1)	I_{DP}	15	Α	
Drain power dissipation	n	P _D	100	W	
Single pulse avalanche energy (Note 2)		E _{AS}	370	mJ	
Avalanche current		I _{AR}	5	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	10	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	1.25	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	83.3	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

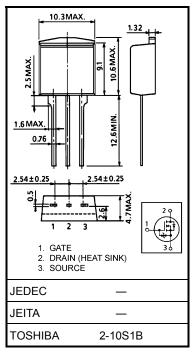
Note 2: V_{DD} = 90 V, T_{Ch} = 25°C (initial), L = 27 mH, R_G = 25 Ω ,

Note 3: Repetitive rating: pulse width limited by maximum channel temperature.

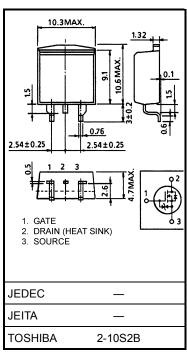
This transistor is an electrostatic-sensitive device.

Please handle with caution.

Unit: mm



Weight: 1.5 g (typ.)



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Electrical Characteristics (Ta = 25°C)

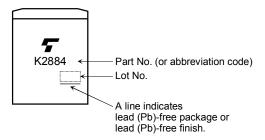
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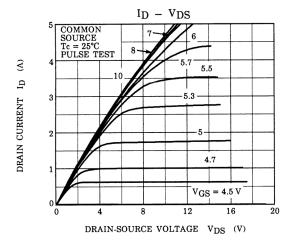
Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±30 V, V _{DS} = 0 V	_	_	±10	μΑ
Gate-source bre	eakdown voltage	V (BR) GSS	I _G = ±10 μA, V _{DS} = 0 V	±30	_	_	V
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 640 V, V _{GS} = 0 V	_	_	100	μA
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	800	_	_	V
Gate threshold v	oltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source O	N resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 3 A	_	1.9	2.2	Ω
Forward transfer	r admittance	Y _{fs}	V _{DS} = 15 V, I _D = 3 A	1.0	3.8	_	S
Input capacitano	e	C _{iss}		_	1080	_	
Reverse transfe	r capacitance	C _{rss}	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz	_	16	_	рF
Output capacitance		C _{oss}		_	105	_	
Switching time	Rise time	t _r	V_{GS} V_{OUT} V_{OUT} V_{DD} V_{DD} V_{DD} V_{DD} V_{DD}	_	40	_	
	Turn-on time	t _{on}			80		ne
	Fall time	t _f		_	40	_	ns
	Turn-off time	t _{off}		_	140	_	
Total gate charge (gate-source plus gate-drain)		Qg			34		nC
Gate-source charge		Q _{gs}	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$		16		
Gate-drain ("miller") Charge		Q_{gd}			18	_	

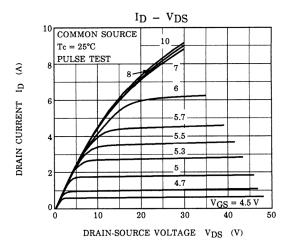
Source-Drain Ratings and Characteristics (Ta = 25°C)

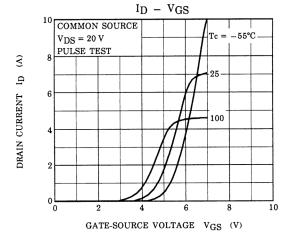
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	$I_{ m DR}$	_	-	_	5	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	-	_	15	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 5 A, V _{GS} = 0 V		_	-1.9	V
Reverse recovery time	t _{rr}	I _{DR} = 5 A, V _{GS} = 0 V	_	1000	_	ns
Reverse recovery charge	Q _{rr}	dl _{DR} / dt = 100 A / µs	_	7.5	_	μC

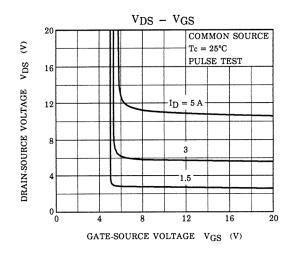
Marking

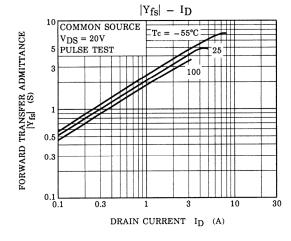


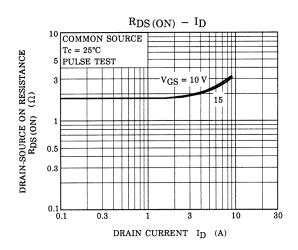


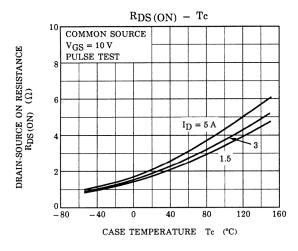


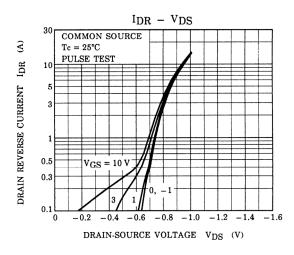


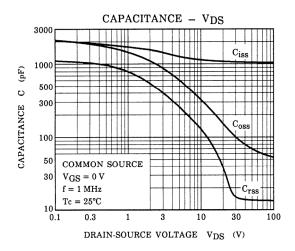


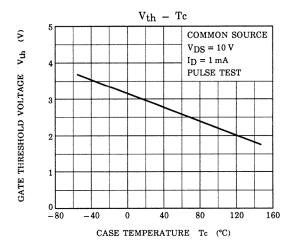


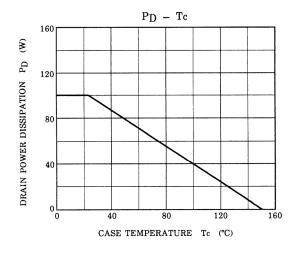


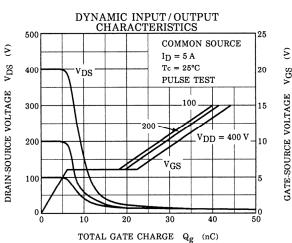


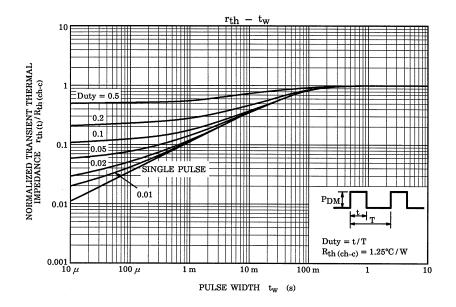


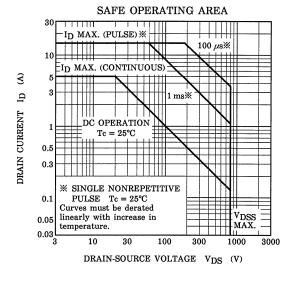


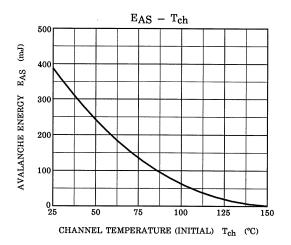


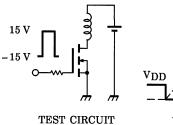


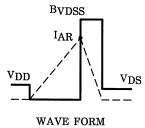












$$R_G$$
 = 25 Ω
 V_{DD} = 90 V, L = 27 mH

$$EAS = \frac{1}{2} \cdot L \cdot I^{2} \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right)$$

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Handbook" etc..

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